

10/782,030

FORM PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION <i>(Use several sheets if necessary)</i>	Docket Number (Optional) 83394.0024	Application Number ⁷ Not Assigned (Parent 10/421,140)
	Applicant KAZUI, et al.	
	Filing Date February 19, 2004	Group Art Unit Not Assigned 2883

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
CML	2003/0010914		TAKANE, et al.			01/16/2003

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
CML	07-027549	01/27/95	JAPAN			Abstract	
CML	02-247964	10/03/90	JAPAN			Abstract	
CML	05-290786	11/05/93	JAPAN			Abstract	
CML	01-143127	06/05/89	JAPAN			Abstract	
CML	63-032314	02/12/88	JAPAN			Abstract	
CML	61-290313	12/20/86	JAPAN			Abstract	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

CML	Karsushi IKEUCHI, "Determining 3D Shape from 2D Shading Information Based on the Reflectance Map Technique", IEICE Transactions, Vol. J-65-D, No. 7, pp. 842-849, issued by the Institute of Electronics, Information and Communication Engineers, in July, 1982
CML	ALLGAIR, et al., "Implementation of Spectroscopic Critical Dimension (SCD) for Gate CD Control and Stepper Characterization", Metrology, Inspection, and Process Control for Microlithography XV, Proceedings of SPIE Vol. 4344 (2001), pgs. 462-471

EXAMINER Chris Kalwood	DATE CONSIDERED August 6, 2004
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.	